Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,796	LEE ET AL.	
Examiner	Art Unit	
David C. Pavne	2613	

	SEAR	CHED	
Class	Subclass	Date	Examiner
398	154, 155	10/2/2006	DCP
398	183, 201	10/2/2006	DCP
398	147, 212	10/2/2006	DCP
398	214, 209	10/2/2006	DCP 。

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

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